Application/Control No. Applicant(s)/Patent Under Reexamination 10/059,635 WEI ET AL. Notic of References Cited Examiner Art Unit Page 1 of 1 1615 Simon J. Oh **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY Α US-5595759 01-1997 Wright et al. 424/464 06-2002 В US-6406738 B1 Hogan et al. 427/2.14 US-С US-D US-Ε US-F G US-US-Н US-US-J Κ US-US-L M US-FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W Х

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